

Notice of References Cited	Application/Control No. 10/619,835	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Chriss S. Yoder, III	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,896,166 A	04-1999	D'Alfonso et al.	348/72
*	B	US-6,873,366 B2	03-2005	Tashiro et al.	348/312
*	C	US-2004/0119844 A1	06-2004	Aldrich et al.	348/231.99
*	D	US-6,046,769 A	04-2000	Ikeda et al.	348/222.1
*	E	US-6,980,241 B2	12-2005	Aruga et al.	348/241
*	F	US-6,593,963 B1	07-2003	Safai, Mohammad A.	348/222.1
*	G	US-7,042,499 B1	05-2006	Kido et al.	348/211.14
*	H	US-6,313,868 B1	11-2001	D'Alfonso et al.	348/72
*	I	US-6,573,931 B1	06-2003	Horii et al.	348/211.14
*	J	US-5,040,068	08-1991	Parulski et al.	348/376
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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